Search Notes
] (BB) P1 (121) 2010) B) P1 (ID)   1010   1010   1212   1010   1211   1001
1 100101 1111 100101 11110 11110 1010 1010 1010 1010 1010 1010 1010 1010 1010 1010 1010 1010 1010 1010 1010 1

Application/Control No.	Applicant(s)/Patent under Reexamination	Applicant(s)/Patent under Reexamination	
10/519,988	SCHARNWEBER ET AL.		
Examiner	Art Unit		
Young J. Kim	1637		

SEARCHED			
Class	Subclass	Date	Examiner
-			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
<u> </u>			

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	8/22/2007	YJK
		į